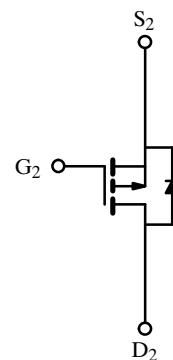
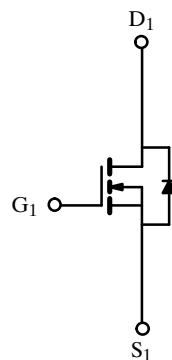


Dual Enhancement-Mode MOSFET (N- and P- Channel)

Product Summary

	V_{DS} (V)	$r_{DS(on)}$ (Ω)	I_D (A)
N-Channel	20	0.08 @ $V_{GS} = 4.5$ V	± 2.8
		0.11 @ $V_{GS} = 2.5$ V	± 2.1
P-Channel	-12	0.1 @ $V_{GS} = -4.5$ V	± 2.5
		0.18 @ $V_{GS} = -2.5$ V	± 1.9

Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

Parameter	Symbol	N-Channel	P-Channel	Unit
Drain-Source Voltage	V_{DS}	20	-12	V
Gate-Source Voltage	V_{GS}	± 8		
Continuous Drain Current ($T_J = 150^\circ\text{C}$) ^a	I_D	± 2.8	± 2.5	A
		± 2.3	± 2.0	
Pulsed Drain Current	I_{DM}	± 20		A
Continuous Source Current (Diode Conduction) ^a	I_S	1.0	-1.0	
Maximum Power Dissipation ^a	P_D	1.0		W
		0.64		
Operating Junction and Storage Temperature Range	T_J, T_{stg}	-55 to 150		°C

Thermal Resistance Ratings

Parameter	Symbol	N- or P-Channel	Unit
Maximum Junction-to-Ambient ^a	R_{thJA}	125	°C/W

Notes

a. Surface Mounted on FR4 Board, $t \leq 10$ sec.

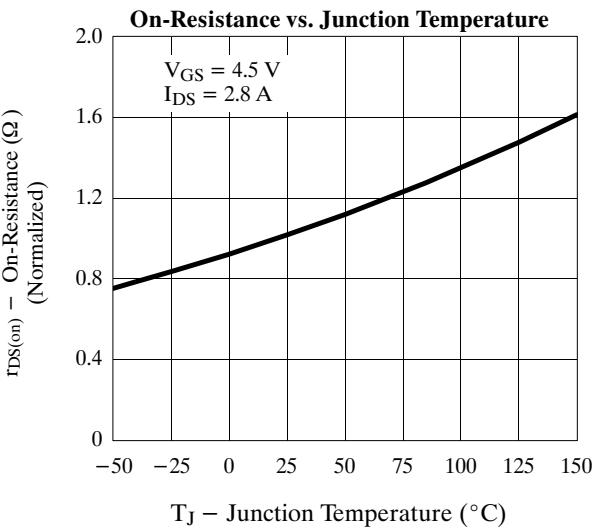
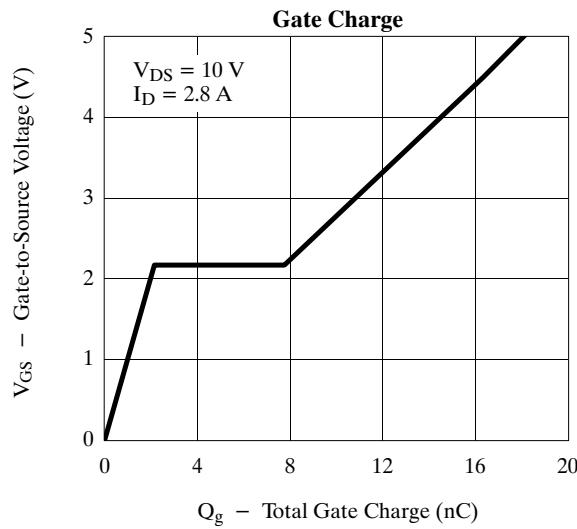
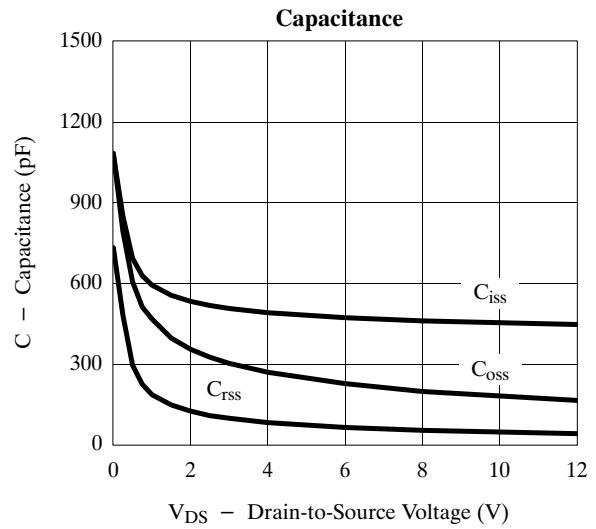
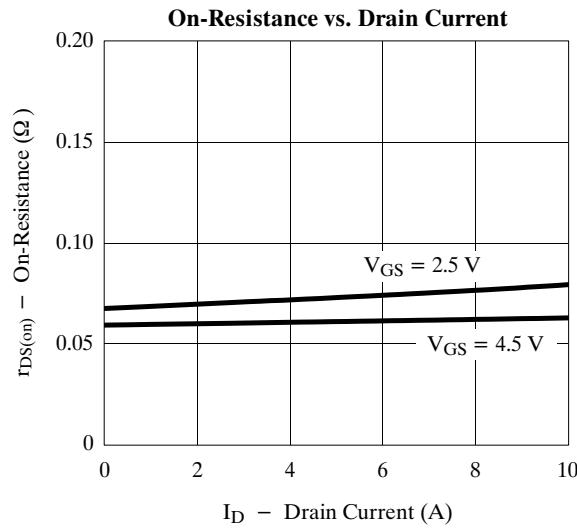
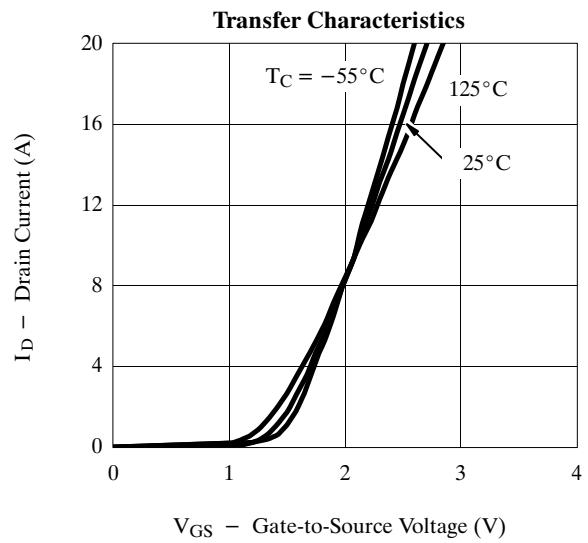
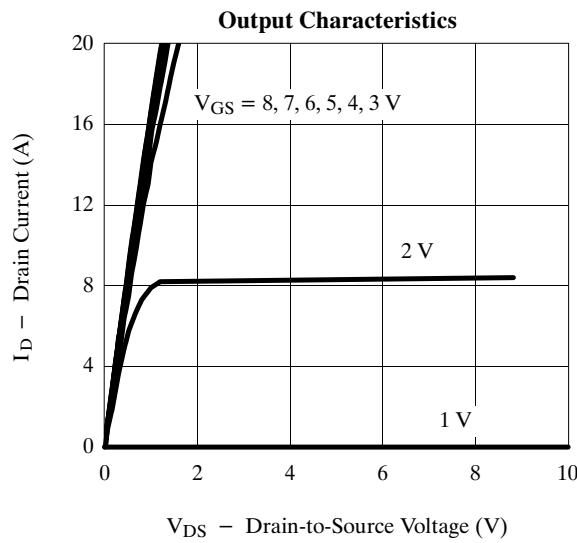
Subsequent updates to this data sheet may be obtained via facsimile by calling Siliconix FaxBack, 1-408-970-5600. Please request FaxBack document #1808.

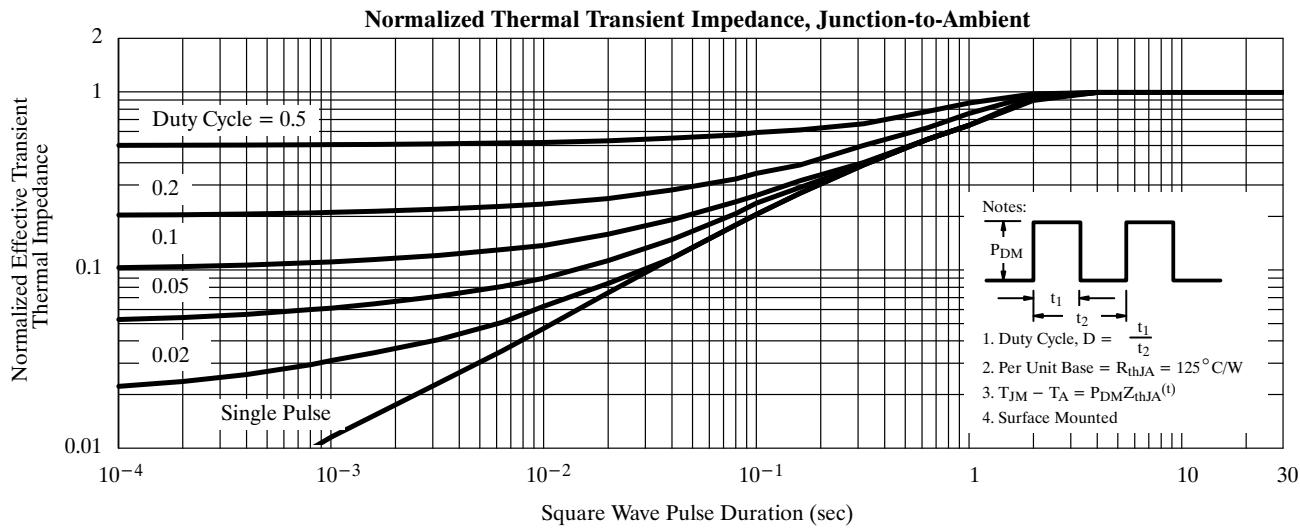
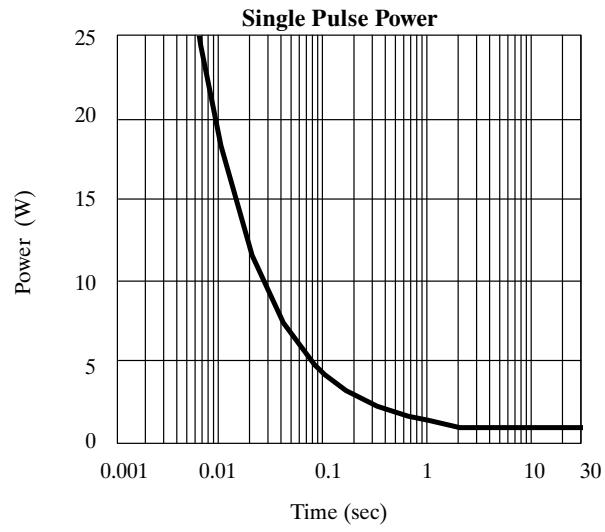
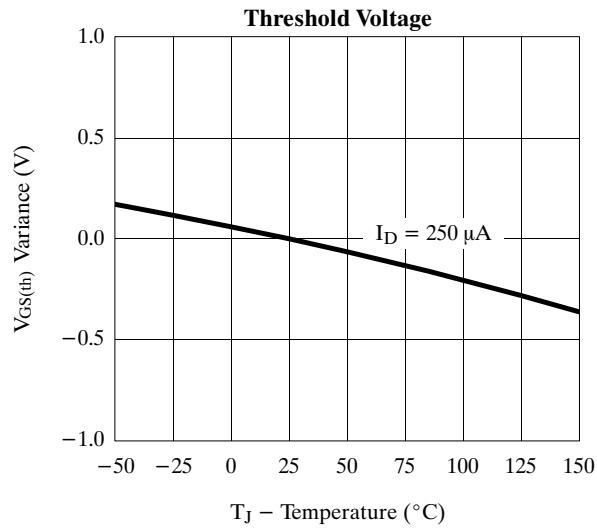
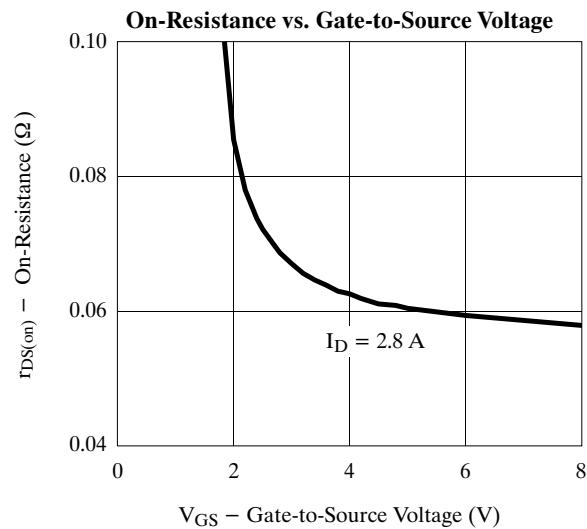
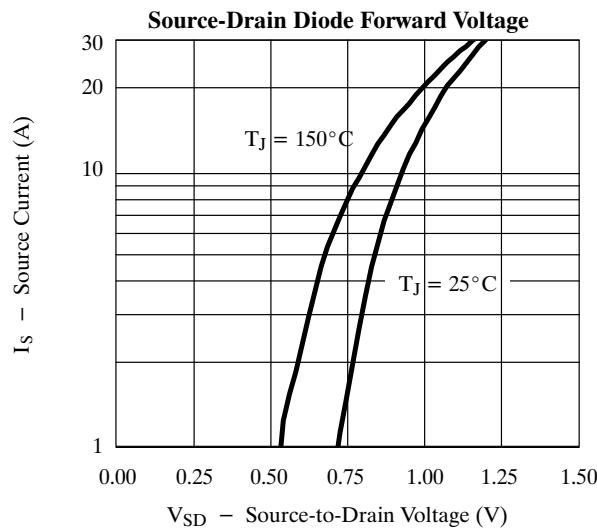
Si6552DQ**Specifications ($T_J = 25^\circ\text{C}$ Unless Otherwise Noted)**

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Static						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	N-Ch	0.6		
		$V_{DS} = V_{GS}, I_D = -250 \mu\text{A}$	P-Ch	-0.6		V
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 8 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}$	N-Ch		1	
		$V_{DS} = -12 \text{ V}, V_{GS} = 0 \text{ V}$	P-Ch		-1	μA
		$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 70^\circ\text{C}$	N-Ch		5	
		$V_{DS} = -12 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 70^\circ\text{C}$	P-Ch		-5	
On-State Drain Current ^a	$I_{D(on)}$	$V_{DS} = 5 \text{ V}, V_{GS} = 4.5 \text{ V}$	N-Ch	10		
		$V_{DS} = -5 \text{ V}, V_{GS} = -4.5 \text{ V}$	P-Ch	-10		A
		$V_{DS} = 5 \text{ V}, V_{GS} = 2.5 \text{ V}$	N-Ch	4		
		$V_{DS} = -5 \text{ V}, V_{GS} = -2.5 \text{ V}$	P-Ch	-4		
Drain-Source On-State Resistance ^a	$r_{DS(on)}$	$V_{GS} = 4.5 \text{ V}, I_D = 2.8 \text{ A}$	N-Ch		0.08	
		$V_{GS} = -4.5 \text{ V}, I_D = 2.5 \text{ A}$	P-Ch		0.1	Ω
		$V_{GS} = 2.5 \text{ V}, I_D = 2.1 \text{ A}$	N-Ch		0.11	
		$V_{GS} = -2.5 \text{ V}, I_D = 1.9 \text{ A}$	P-Ch		0.18	
Forward Transconductance ^a	g_{fs}	$V_{DS} = 15 \text{ V}, I_D = 2.8 \text{ A}$	N-Ch			S
		$V_{DS} = -9 \text{ V}, I_D = -2.5 \text{ A}$	P-Ch			
Diode Forward Voltage ^a	V_{SD}	$I_S = 1.0 \text{ A}, V_{GS} = 0 \text{ V}$	N-Ch		1.2	
		$I_S = -1.0 \text{ A}, V_{GS} = 0 \text{ V}$	P-Ch		-1.2	V
Dynamic^b						
Total Gate Charge	Q_g	N-Channel $V_{DS} = 10 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 2.8 \text{ A}$ P-Channel $V_{DS} = -6 \text{ V}, V_{GS} = -4.5 \text{ V}, I_D = -2.5 \text{ A}$	N-Ch		16	40
Gate-Source Charge	Q_{gs}		P-Ch		9	20
Gate-Drain Charge	Q_{gd}		N-Ch		3	
Gate-Drain Charge	Q_{gd}		P-Ch		2	
Turn-On Delay Time	$t_{d(on)}$	N-Channel $V_{DD} = 10 \text{ V}, R_L = 10 \Omega$ $I_D \approx 1 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_G = 6 \Omega$ P-Channel $V_{DD} = -6 \text{ V}, R_L = 6 \Omega$ $I_D \approx -1 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_G = 6 \Omega$	N-Ch		37	60
Rise Time	t_r		P-Ch		21	40
Turn-Off Delay Time	$t_{d(off)}$		N-Ch		66	100
Fall Time	t_f		P-Ch		35	70
Source-Drain Reverse Recovery Time	t_{rr}	N-Channel— $I_F = 1.0 \text{ A}, di/dt = 100 \text{ A}/\mu\text{s}$ P-Channel— $I_F = -1.0 \text{ A}, di/dt = 100 \text{ A}/\mu\text{s}$	N-Ch		56	100
			P-Ch		43	80
			N-Ch		57	100
			P-Ch		22	40
			N-Ch		26	70
			P-Ch		35	70

Notes

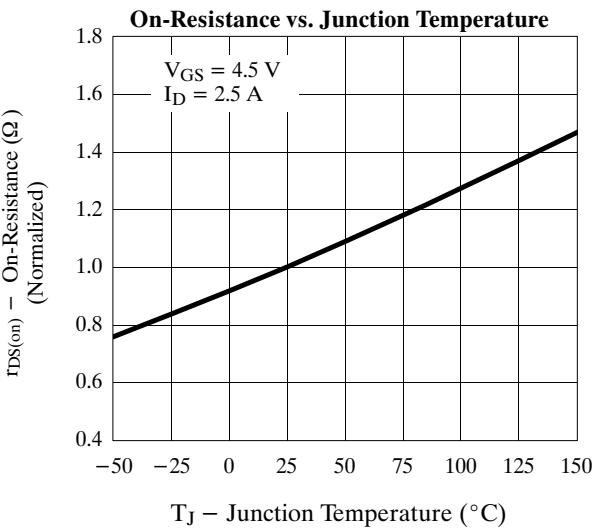
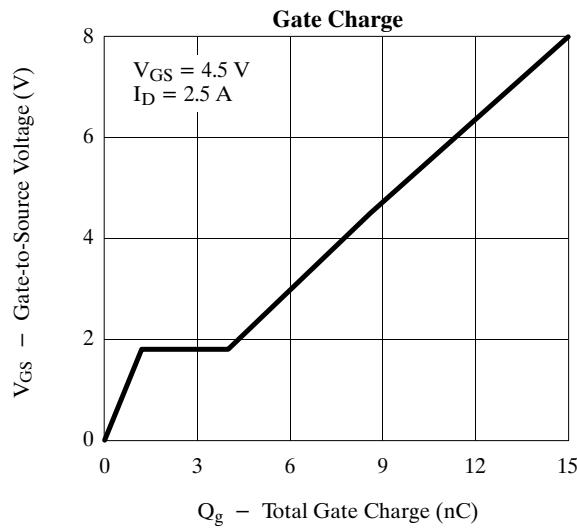
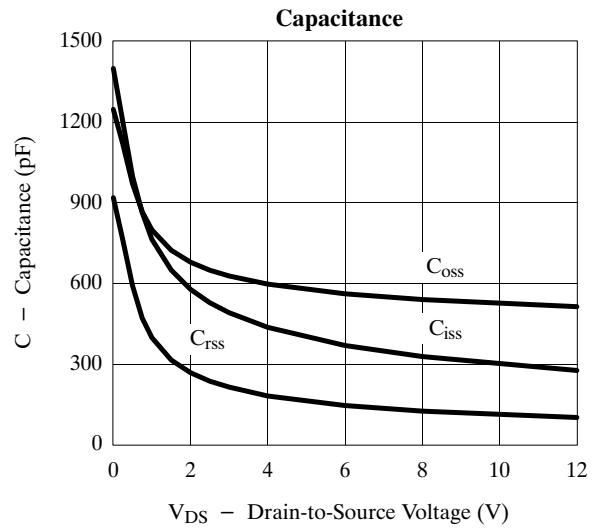
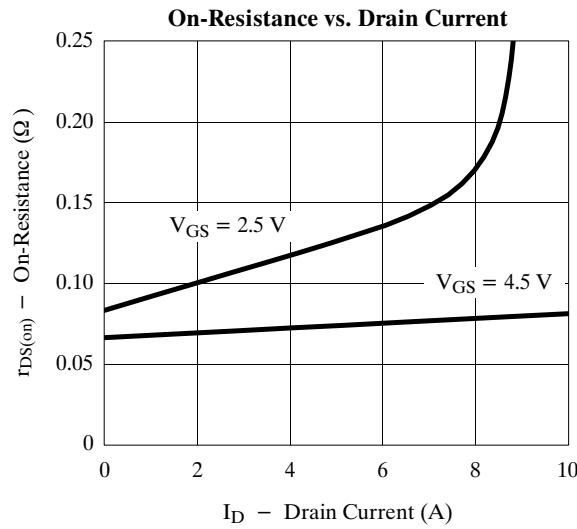
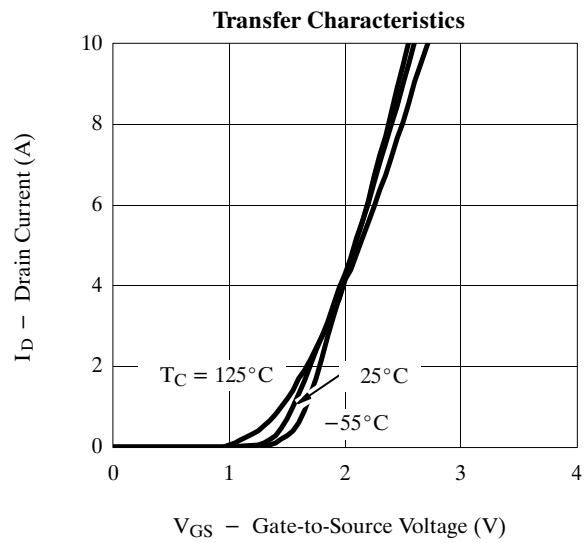
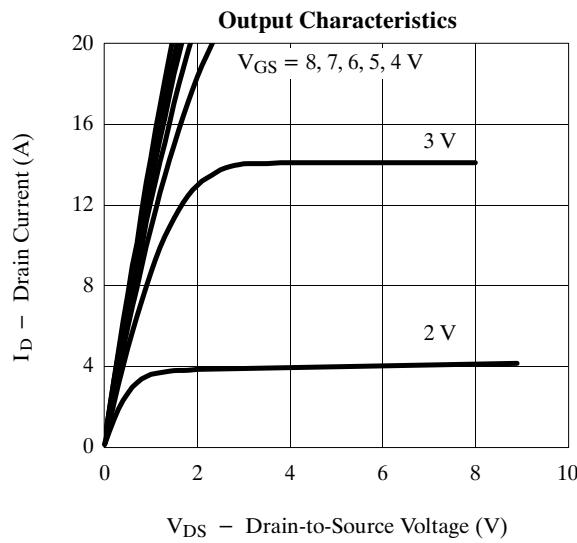
- a. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.
 b. Guaranteed by design, not subject to production testing.

Typical Characteristics (25°C Unless Noted)**N-Channel**

Si6552DQ**Typical Characteristics (25°C Unless Noted)****N-Channel**

Typical Characteristics (25°C Unless Noted)

P-Channel



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Si6552DQ

Typical Characteristics (25°C Unless Noted)

P-Channel

